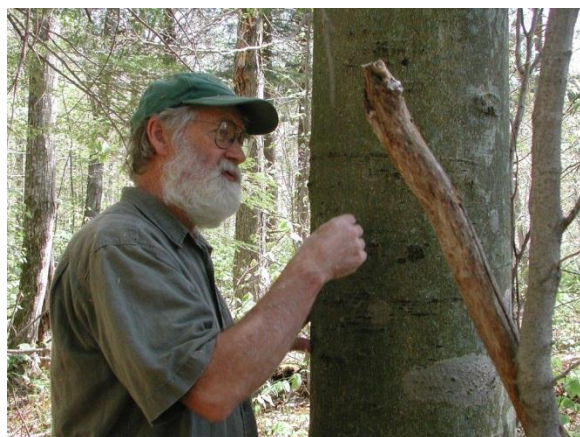


Lockwood Lecture

Wednesday, 23 May 2012



Dr. Houston at work studying beech bark disease

Dr. David R. Houston will be coming to The Connecticut Agricultural Experiment Station to deliver a Lockwood Lecture titled “Beech Bark Disease: Biology, Ecology, and Forest Responses. A Five-Decade Quest for Understanding.” The lecture will take place at 10:30 am (tea at 10:00 am) on 23 May 2012 in the Experiment Station’s Jones Auditorium at 123 Huntington Street in New Haven, Connecticut.

Dr. Houston is a world-renowned forest pathologist whose decades of research have focused on the complexities of dieback-decline diseases of deciduous hardwoods. In particular, Dr. Houston has been interested in determining and clarifying the causal relationships and ecological factors associated with patterns of disease development over time and space. This systems approach began during his tenure at the University of Wisconsin where, from 1958 to 1961, he conducted research on the insect/disease complex causing Maple Blight. Since then, he has applied this approach and perspective to a variety of hardwood species, including ash, oak, maple

and, of course, beech. More recently, Dr. Houston has been studying the introduced European Larch Canker disease as it manifests on American Larch in Maine.

Dr. Houston’s work on Beech Bark Disease, which began in the early 1970s and continues to this day, was instrumental in untangling the ecological and epidemiological factors underlying the progression of disease, from infestation by the exotic scale insect, to colonization by two fungal species and concomitant host response in beech trees.

Dr. Houston earned his Ph.D. from the University of Wisconsin, a M.F. from Yale University, and a B.S. from the University of Massachusetts. He is the author of over 120 publications.

This lecture qualifies for 1.0 credit hour for CT pesticide license 3D (arborist) and 1.0 CEU for CT Certified Forest Practitioners (any level).



Beech bark disease in a Nova Scotia forest